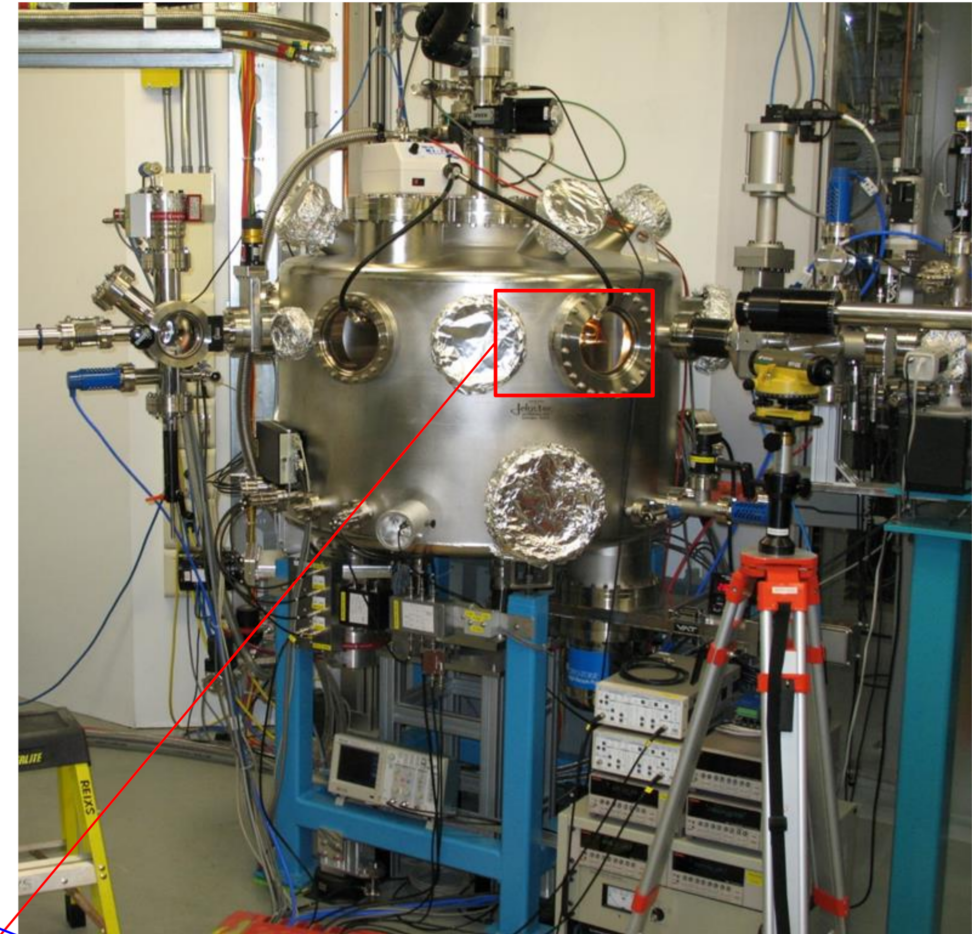
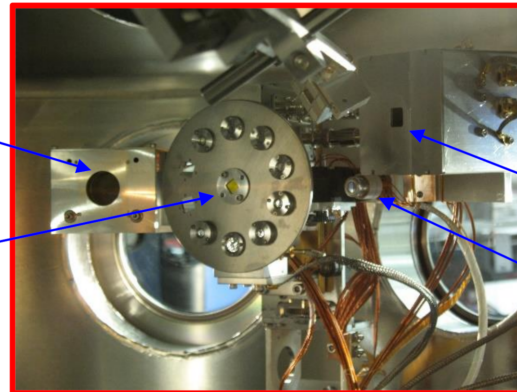


Resonant Soft X-ray Scattering Endstation (RSXS)

Vacuum	$\approx 5 \times 10^{-10}$ Torr
Sample Stage	Four-circle Diffractometer
Sample Temperature	20 – 420 K
Detectors	<ul style="list-style-type: none">- Silicon Drift Detector: 250 – 2500 eV- Micro-channel Plate w/ position readout (100um)- Filter/Slit Wheel with Photodiode or CEM- Polarization Analyzer (4 multi-layers)
Sample Environment	<ul style="list-style-type: none">- Static Magnetic Field- Sample Bias (± 500V)
Techniques	<ul style="list-style-type: none">- Resonant Soft X-ray Scattering (RSXS)- Resonant X-ray Reflectivity (RXR)- X-ray Absorption Spectroscopy (XAS)- X-ray Magnetic Circular Dichroism (XMCD)

Micro-Channel Plate w/
Resistive Anode Encoder

Filter/Slit Wheel w/
Photodiode
CEM



Polarization Analyzer

Silicon Drift Detector